

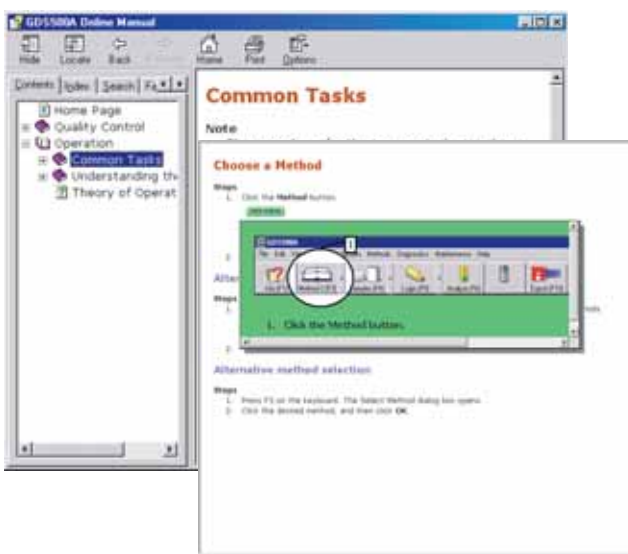
Easy-To-Use Windows®-Based Operating Software

Element	Weight	%	Std. Dev.	Min.	Max.
C	0.0041	0.0041	0.0000	0.0041	0.0041
Si	0.0000	0.0000	0.0000	0.0000	0.0000
Mn	0.0000	0.0000	0.0000	0.0000	0.0000
P	0.0000	0.0000	0.0000	0.0000	0.0000
S	0.0000	0.0000	0.0000	0.0000	0.0000
Cr	0.0000	0.0000	0.0000	0.0000	0.0000
Ni	0.0000	0.0000	0.0000	0.0000	0.0000

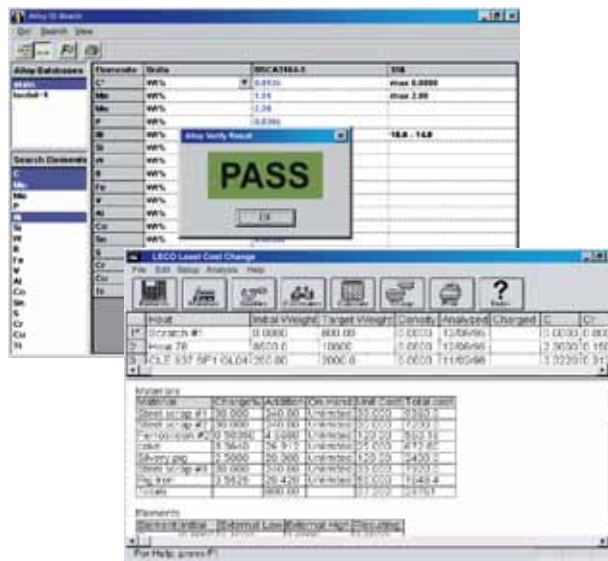
Element	Weight	%	Std. Dev.	Min.	Max.
C	0.0041	0.0041	0.0000	0.0041	0.0041
Si	0.0000	0.0000	0.0000	0.0000	0.0000
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P	0.0000	0.0000	0.0000	0.0000	0.0000
S	0.0000	0.0000	0.0000	0.0000	0.0000
Cr	0.0000	0.0000	0.0000	0.0000	0.0000
Ni	0.0000	0.0000	0.0000	0.0000	0.0000

User-Defined Quality Control and Flexible Interface

★ = Passes acceptance criteria ▼ = failed acceptance criteria • Review analyses and statistics in a table or graphical format • User options easily customized to print, transmit, and store results.



On-Board Help Manual for Quick Reference



Side-by-Side View of Alloy ID and Least Cost Charge

Options

- Alloy ID software
- Least cost charge software
- NWA quality analyst software
- Touchscreen color monitor
- Deskjet/dot matrix printer kits
- SmartLine® Remote Diagnostics
- Sample holders
- Sample preparation equipment

Sample Holders

A variety of sample holders are available to meet your needs.



LECO GDS500A

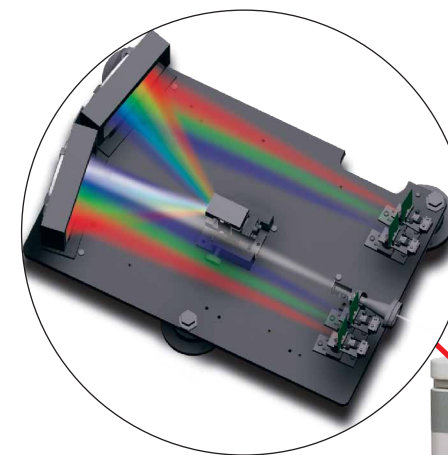
Technology designed for routine production, process, and quality control

LECO's CCD-based Glow Discharge Atomic Emission Spectrometer (AES) offers you state-of-the-art technology designed specifically for routine elemental determination in most ferrous and nonferrous materials. The GDS500A features improved performance, stability, accuracy, and precision in steel, iron (including as-cast), aluminum, copper, zinc, nickel, cobalt, tungsten, and titanium. Low melting alloys, resulfurized steel, powder metals, and other difficult materials can be run in a production environment.

Sample types include bulk, sheet, wire, pressed, and mounted samples. Sample holders are available to meet non-standard sample forms.

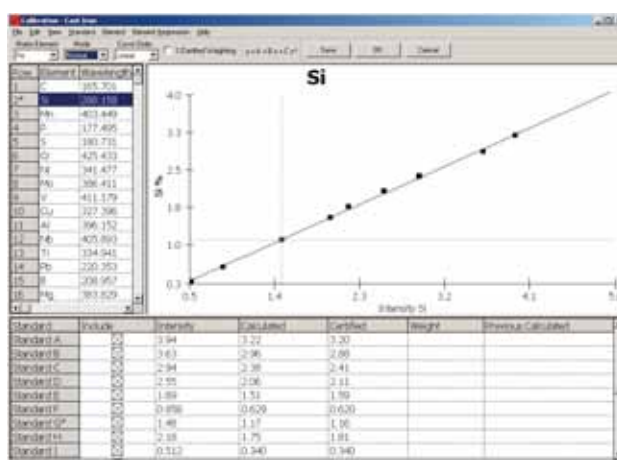
LECO GD-AES Advantage

- Linear calibrations with wide dynamic range
- Uniform sample excitation offers improved precision
- Freedom from metallurgical history
- Low Ar gas consumption reduces cost per test
- Separation of sample sputtering from excitation
- Quick matrix change with minimal memory effects
- Auto cleaning between analyses



Solid-State Technology

LECO's exclusive CCD-based design ensures stability, flexibility, and performance for ferrous and nonferrous applications. Full wavelength coverage from 165 nm to 460 nm.



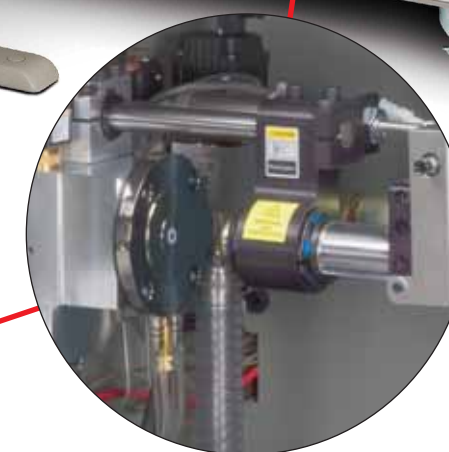
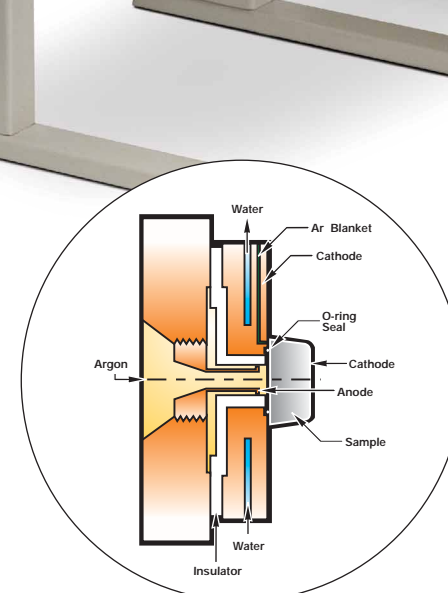
Simple, Linear Calibrations

GD-AES provides narrow emission lines, less interference, and less complex spectra when compared to other sources.



Windows®-Based, Quality Control Oriented Software

Offers user-defined quality control features for analysis and acceptance to match your requirements. On-board help manual and available **SmartLine** Remote Diagnostics support add convenience and ease-of-use.



Controlled Excitation

GD-AES provides a non-thermal source to uniformly remove sample material from the surface. Excitation of the sample occurs away from the surface, reducing chemical and metallurgical effects.